



Product Name: 2G 2PORT Serial Device Server

Model No. : NPort 5230, 5230-N, NPort 5230-P, NPort 5230-T

FCC ID. : DoC

Applicant: Moxa Technologies CO., LtD

Address: Fl.4, No. 135, Lane 235, Pao-Chiao Rd., Shing

Tien City, Taipei, Taiwan, R.O.C.

Date of Receipt: Mar. 14, 2003

Issued Date : Jul. 26, 2005

Report No. : 033L112F

The test results relate only to the samples tested.

The test report shall not be reproduced except in full without the written approval of QuieTek Corporation. This report must not be used to claim product endorsement by NVLAP any agency of the U.S. Government

Page: 1 of 18 Version: 1.0

DECLARATION OF CONFORMITY

Per FCC Part 2 Section 2. 1077(a)



The following equipment:				
Product Name : 2G 2PORT Serial Device Server				
Trade Name : Moxa				
Model Number : NPort 5230, 5230-N, NPort 5230-P, NPort 5230-T				
It's herewith confirmed to comply with the requirements of FCC Part 15 Rules.				
Operation is subject to the following two conditions:				
(1) This device may not cause harmful interference, and				
(2) This device must accept any interference received, including interference that				
may cause undesired operation.				
The result of electromagnetic emission has been evaluated by QuieTek EMC				
laboratory (NVLAP Lab. Code : <u>200533-0</u>) and showed in the test report.				
(Report No. : <u>QTK-033L112F</u>				
(Tepot/16.: <u>QTIT 955BTI21</u>				
It is understood that each unit marketed is identical to the device as tested, and				
Any changes to the device that could adversely affect the emission				
Characteristics will require retest.				
Characteristics will require retest.				
The following importer / manufacturer is responsible for this declaration:				
Company Name				
Company Address				
Telephone Facsimile:				
Person is responsible for marking this declaration:				
Terson is responsible for marking this accidentation.				
Name (Full name) Position / Title				
Name (Full name) Position / Title				
Name (Full name) Position / Title				
Name (Full name) Position / Title Date Legal Signature				



Test Report Certification

Issued Date: Jul. 26, 2005 Report No.: 033L112F



Accredited by NIST (NVLAP) NVLAP Lab Code: 200533-0

Product Name : 2G 2PORT Serial Device Server

Applicant : Moxa Technologies CO., LtD

Address : Fl.4, No. 135, Lane 235, Pao-Chiao Rd., Shing Tien City, Taipei, Taiwan,

R.O.C.

Manufacturer : Moxa Technologies CO., LtD

Model No. : NPort 5230, 5230-N, NPort 5230-P, NPort 5230-T

FCC ID. : DoC Rated Voltage : 12Vdc

Trade Name : Moxa

Measurement Standard : FCC Part 15 Subpart B:2002, CISPR22: 1997

Measurement Procedure : ANSI C63.4:1992

Classification : Class A

Test Result : Complied

The test results relate only to the samples tested.

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This report must not be used to claim product endorsement by NVLAP any agency of the U.S. Government

Documented By :

(Gina Chen

Tested By :

(Sky Hsu)

Approved By :

(Gene Chang)

Page: 2 of 18 Version: 1.0



Reference : Laboratory of License

TABLE OF CONTENTS

Desci	Tipuon	Page
1.	GENERAL INFORMATION	2
1.1.	EUT Description	∠
1.2.	Tested System Details	
1.3.	Configuration of Tested System	6
1.4.	EUT Exercise Software	<i>6</i>
1.5.	Test Facility	
2.	Conducted Emission	
2.1.	Test Equipment List	8
2.2.	Test Setup	
2.3.	Limits	9
2.4.	Test Procedure	9
2.5.	Test Result	9
3.	Radiated Emission	10
3.1.	Test Equipment	10
3.2.	Test Setup	
3.3.	Limits	11
3.4.	Test Procedure	11
3.5.	Test Result	11
4.	EMI Reduction Method During Compliance Testing	12
5.	Summary of Test Datas	13
5.1.	Test Result of Conducted Emission	14
5.2.	Test Result of Radiated Emission	15
Attachm	nent 1: EUT Test Photographs	
	nent 2: EUT Detailed Photographs	
1 Ittaciiii	ion 2. Do i Dountou i notographo	



1. GENERAL INFORMATION

1.1. EUT Description

Product Name : 2G 2PORT Serial Device Server

Trade Name : Moxa

Model No. : NPort 5230, 5230-N, NPort 5230-P, NPort 5230-T

Rated Voltage : 12Vdc

PC Chassis : Chenbro, B6251-200 Mother Board : Biostar, M6TSS

CPU : CELERON(TM)500MHZ , Clock: 100MHz

HDD : Seagate , ST310212A CD-ROM : HITACHI, CDR-7930 FDD : MISUMI, D353M3D VGA Card : ASUS, AGPV3000ZX

Sound Card : On Board

LAN Card : Dlink , DFE-530TX

SPS DELTA, Dsp-200PB-126A

Power Cord : Non-Shielded, 1.8m

Note:

- 1. The EUT is including four models for different marketing requirement.
- 2. QuieTek has verified the construction and function in typical operation. All the test modes were carried out with the EUT in normal operation, which was shown in this test report and defined as:

EMI Mode Mode1: Simulate Test Program

Page: 4 of 18 Version: 1.0



1.2. Tested System Details

The types for all equipment, plus descriptions of all cables used in the tested system (including inserted cards) are:

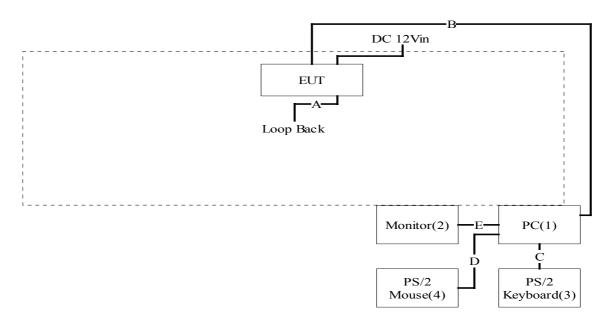
	Product	Manufacturer	Model No.	Serial No.	FCC ID	Power Cord
(1.)	PC	N/A	N/A	N/A	N/A	N/A
(2.)	Monitor	ADI	CM703	038054T10203891A	DoC	Non-Shielded, 1.8m
(3.)	PS/2Keyboard	Acer	6311-TW4C/6	N/A	DoC	N/A
(4.)	Mouse	НІТАСНІ	PC-KM1300	N/A	JNZ201213	N/A

	Signal Cable Type	Signal Cable Description		
A.	Lan Cable (Loop Back)	Shielded, 0.8m		
B.	Lan Cable	Shielded, 7m		
C.	PS/2 Keyboard Cable	Shielded, 1m		
D.	PS/2 Mouse Cable	Shielded, 1m		
E.	VGA Cable	Shielded, 1.8m, a ferrite core bonded		

Page: 5 of 18 Version:1.0



1.3. Configuration of Tested System



1.4. EUT Exercise Software

- (1) Setup the EUT and simulators as shown on 1.3.
- (2) Turn on the power of all equipment.
- (3) Boot the PC from Hard Disk.
- (4) Data will be communicated between computer and EUT.
- (5) The personal computer monitors' will show the transmitting and receiving characteristics when the communication is success.
- (6) Repeat the above procedure (4) to (5).

Page: 6 of 18 Version: 1.0



1.5. Test Facility

Ambient conditions in the laboratory:

Items	Required (IEC 68-1)	Actual
Temperature (°C)	15-35	20-35
Humidity (%RH)	25-75	50-65
Barometric pressure (mbar)	860-1060	950-1000

Site Description: June 22, 2001 File on

Federal Communications Commission

FCC Engineering Laboratory 7435 Oakland Mills Road Columbia, MD 21046

Reference 31040/SIT1300F2

July 03, 2001 Accreditation on NVLAP

NVLAP Lab Code: 200533-0

Site Name: Quietek Corporation

Site Address: No. 5-22, Ruei-Shu Valley, Ruei-Ping Tsuen,

Lin Kou Shiang, Taipei 244 Taiwan, R.O.C.

TEL: 886-2-8601-3788 / FAX: 886-2-8601-3789

E-Mail: service@quietek.com





2. Conducted Emission

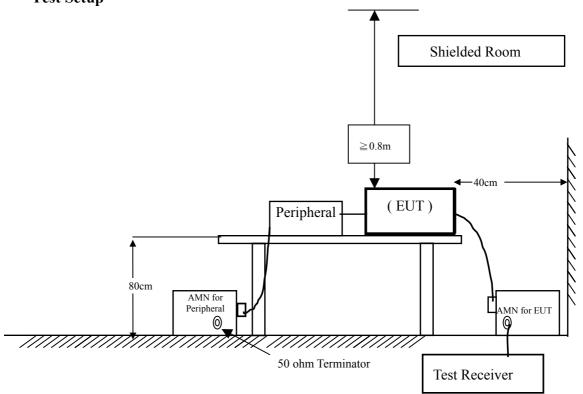
2.1. Test Equipment List

The following test equipment are used during the conducted emission test:

Item	Instrument	Manufacturer	Type No./Serial No	Last Cal.	Remark
1	Test Receiver	R & S	ESCS 30/838251/0001	May, 2002	
2	L.I.S.N.	R & S	ESH3-Z5/836679/0023	May, 2002	EUT
3	L.I.S.N.	R & S	ENV 4200/833209/0023	May, 2002	Peripherals
4	Pulse Limiter	R & S	ESH3-Z2	May, 2002	
5	No. 4 Shielded Roo	om		N/A	

Note: All equipment upon which need to calibrated are with calibration period of 1 year.

2.2. Test Setup



Page: 8 of 18 Version: 1.0



2.3. Limits

FCC Part 15 Subpart B Limits (dBuV)					
Frequency MHz	Clas	ss A	Class B		
	QP	AV	QP	AV	
0.15 - 0.50	79	66	66-56	56-46	
0.50-5.0	73	60	56	46	
5.0 - 30	73	60	60	50	

Remarks: In the above table, the tighter limit applies at the band edges.

2.4. Test Procedure

The EUT and simulators are connected to the main power through a line impedance stabilization network (L.I.S.N.). This provides a 50 ohm /50uH coupling impedance for the measuring equipment. The peripheral devices are also connected to the main power through a LISN that provides a 50ohm/50uH coupling impedance with 50ohm termination. (Please refers to the block diagram of the test setup and photographs.)

Both sides of A.C. line are checked for maximum conducted interference. In order to find the maximum emission, the relative positions of equipment and all of the interface cables must be changed according to ANSI C63.4:1992 on conducted measurement.

Conducted emissions were invested over the frequency range from 0.15MHz to 30MHz using a receiver bandwidth of 9kHz.

2.5. Test Result

The emission from the EUT was below the specified limits. The worst-case emissions are shown in section 5. The acceptance criterion was met and the EUT passed the test.

Page: 9 of 18 Version: 1.0



3. Radiated Emission

3.1. Test Equipment

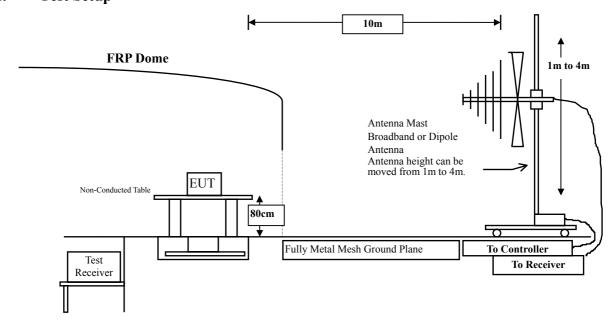
The following test equipment are used during the radiated emission test:

Test Site	Equipment	Manufacturer	Model No./Serial No.	Last Cal.
☐Site # 1	Test Receiver	R & S	ESVS 10 / 834468/003	July, 2002
	Spectrum Analyzer	Advantest	R3162/ 00803480	May, 2002
	Pre-Amplifier	Advantest	BB525C/ 3307A01812	May, 2002
	Bilog Antenna	SCHAFFNER	CBL6112B / 2697	Nov., 2002
☐Site # 2	Test Receiver	R & S	ESCS 30 / 836858 / 022	Nov., 2002
	Spectrum Analyzer	Advantest	3162 / 100803466	May, 2002
	Pre-Amplifier	Advantest	BB525C/3307A01814	May, 2002
	Bilog Antenna	SCHAFFNER	CBL6112B / 2705	Oct., 2002
	Horn Antenna	ETS	3115 / 0005-6160	July, 2002
	Pre-Amplifier	QTK	QTK-AMP-01/0001	July, 2002
∑ Site # 3	Test Receiver	R & S	ESI 26 / 838786 / 004	May, 2002
	Spectrum Analyzer	Advantest	3162 / 100803480	May, 2002
	Pre-Amplifier	QTK	QTK-AMP-03 / 0003	May, 2002
	Bilog Antenna	SCHAFFNER	CBL6112B / 2697	May, 2002
	Horn Antenna	ETS	3115 / 0005-6160	July, 2002
	Pre-Amplifier	QTK	QTK-AMP-01 / 0001	July, 2002

Note: 1. All equipments that need to calibrate are with calibration period of 1 year.

2. Mark "X" test instruments are used to measure the final test results.

3.2. Test Setup



Page: 10 of 18 Version: 1.0



3.3. Limits

According to CISPR 22 Limits (dBuV)					
Frequency	Class A		Class B		
MHz	Distance (m)	dBuV/m	Distance (m)	dBuV/m	
30 – 230	10	40	10	30	
230 – 1000	10	47	10	37	
FCC Part 15 Subpart B Limits (dBuV)					
Above 960	10	49.5	3	54	

Remark: 1. The tighter limit shall apply at the edge between two frequency bands.

- 2. Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the device or system.
- 3. RF Line Voltage $(dBuV/m) = 20 \log RF \text{ Line Voltage } (uV/m)$

3.4. Test Procedure

The EUT and its simulators are placed on a turn table which is 0.8 meter above ground. The turn table can rotate 360 degrees to determine the position of the maximum emission level. The EUT was positioned such that the distance from antenna to the EUT was 10 meters.

The antenna can move up and down between 1 meter and 4 meters to find out the maximum emission level.

Both horizontal and vertical polarization of the antenna are set on measurement. In order to find the maximum emission, all of the interface cables must be manipulated according to ANSI C63.4:1992 on radiated measurement.

Radiated emissions were invested over the frequency range from 30MHz to1GHz using a receiver bandwidth of 120kHz. Radiated was performed at an antenna to EUT distance of 10 meters.

3.5. Test Result

The emission from the EUT was below the specified limits. The worst-case emissions are shown in section 5. The acceptance criterion was met and the EUT passed the test.

Page: 11 of 18 Version: 1.0



4. EMI Reduction Method During Compliance Testing

No modification was made during testing.

Page: 12 of 18 Version:1.0



5. Summary of Test Datas

The test results in the emission was performed according to the requirements of measurement standard and process. Quietek Corporation is assumed full responsibility for the accuracy and completeness of these measurements. The test data of the emission is listed as below.

All the tests were carried out with the EUT in normal operation, which was defined as:

Test Mode:

EMI Mode Mode1: Simulate Test Program

Page: 13 of 18 Version: 1.0



5.1. Test Result of Conducted Emission

Product : 2G 2PORT Serial Device Server

Test Item : Conducted Emission Test

Owing to the DC operation of EUT, this test item is not performed.

Page: 14 of 18 Version:1.0



5.2. Test Result of Radiated Emission

Product : 2G 2PORT Serial Device Server

Test Item : Radiated Emission
Test Site : No.2 OATS

Test Mode : Mode1: Simulate Test Program

	Freq.	Cable		PreAMP			on Margin	n Limit
	MHz	Loss dB	Factor dB/m	dB	Level dBuV	Level dBuV/m	dB	dBuV/m
Но	rizontal	======	=======			=======	======	=========
	66.205	1.05	5.66	0.00	10.86	17.58	22.42	40.00
	116.235	1.31	11.96	0.00	5.12	18.39	21.61	40.00
	124.958	1.36	11.64	0.00	9.26	22.26	17.74	40.00
	177.670	1.63	8.53	0.00	9.09	19.25	20.75	40.00
	200.004	1.74	8.40	0.00	15.01	25.15	14.85	40.00
*	399.995	2.78	14.85	0.00	16.06	33.69	13.31	47.00
	499.995	3.29	16.34	0.00	13.59	33.22	13.78	47.00
	643.328	4.03	18.61	0.00	10.42	33.05	13.95	47.00
	799.995	4.83	19.39	0.00	8.99	33.21	13.79	47.00
Ve	rtical							
	43.520	0.94	9.57	0.00	11.02	21.53	18.47	40.00
	49.490	0.97	6.90	0.00	16.19	24.06	15.94	40.00
	51.885	0.98	6.39	0.00	14.34	21.72	18.28	40.00
	75.120	1.10	6.93	0.00	15.11	23.15	16.85	40.00
	110.728	1.28	11.12	0.00	8.97	21.37	18.63	40.00
	124.995	1.36	10.19	0.00	15.01	26.56	13.44	40.00
	161.915	1.55	8.53	0.00	13.66	23.74	16.26	40.00
	184.569	1.66	8.31	0.00	16.22	26.19	13.81	40.00
*	200.133	1.74	8.40	0.00	16.49	26.63	13.37	40.00
	399.995	2.78	16.45	0.00	13.21	32.44	14.56	47.00
	593.330	3.77	19.76	0.00	8.13	31.65	15.35	47.00
	643.335	4.03	18.04	0.00	10.12	32.19	14.81	47.00

Note:

- 1. All Reading Levels are Quasi-Peak and average value.
- 2. "*" means this data is the worst emission level.
- 3. Measurement Level = Reading Level + LISN Factor + Cable loss.
- 4. "--" mean the average measurement was not performed when the peak measured data under the limit of average detection.

Page: 15 of 18 Version: 1.0



$Attachment \ 1: EUT \ Test \ Photographs$

Page: 16 of 18 Version:1.0



Attachment 1: EUT Test Setup Photographs

Front View of Radiated Test



Back View of Radiated Test



Page: 1 of 1 Version:1.0



Attachment 2 : EUT Detailed Photographs

Page: 17 of 18 Version:1.0

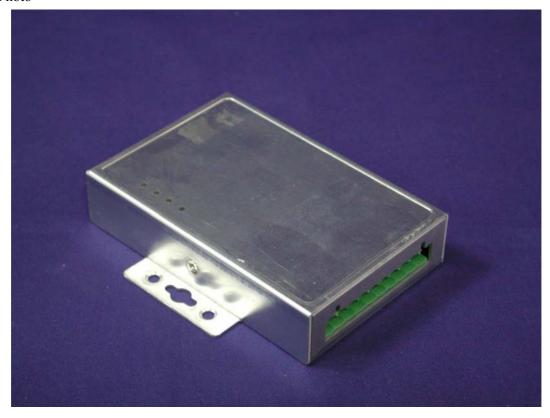


Attachment 2 : EUT Detailed Photographs

(1) EUT Photo



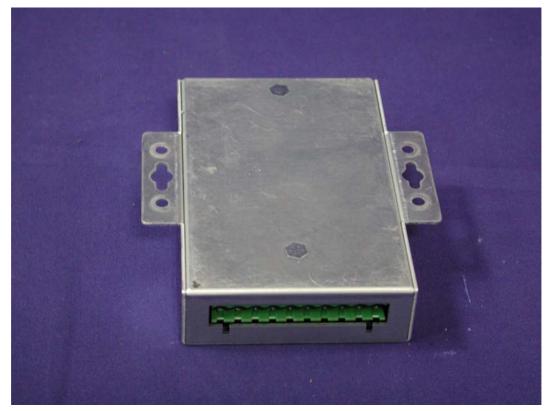
(2) EUT Photo



Page: 1 of 3 Version:1.0



(3) EUT Photo



(4) EUT Photo



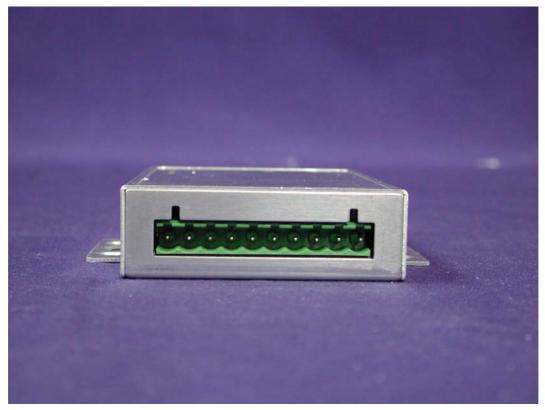
Page: 2 of 3 Version:1.0



(5) EUT Photo



(6) EUT Photo



Page: 3 of 3 Version:1.0



Reference : Laboratory of License

Page: 18 of 18 Version: 1.0

United States Department of Commerce National Institute of Standards and Technology



Certificate of Accreditation to ISO/IEC 17025:1999

NVLAP LAB CODE: 200533-0

Quietek Corporation

Lin Kou Shiang, Taipei 244 TAIWAN is recognized by the National Voluntary Laboratory Accreditation Program for conformance with criteria set forth in Accreditation is granted for specific services, listed on the Scope of Accreditation, for: NIST Handbook 150:2001 and all requirements of ISO/IEC Guide 17025:1999.

ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

2005-07-01 through 2006-06-30

Effective dates



For the National Institute of Standards and Technology



National Voluntary Laboratory Accreditation Program



SCOPE OF ACCREDITATION TO ISO/IEC 17025:1999

Quietek Corporation

No. 5, Ruei-shu Valley, Ruei-ping, Tsuen Lin Kou Shiang, Taipei 244 TAIWAN

Mr. Gene Chang

Phone: 886-2-8601-3788 Fax: 886-2-8601-3789

E-Mail: gene@quietek.com URL: http://www.quietek.com

ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

NVLAP LAB CODE 200533-0

NVLAP Code

Designation / Description

Emissions Test Methods:

12/CIS22

IEC/CISPR 22 (1997) & EN 55022 (1998) + A1(2000): Limits and methods of measurement

of radio disturbance characteristics of information technology equipment

12/CIS22a

IEC/CISPR 22 (1993) and EN 55022 (1994): Limits and methods of measurement of radio

disturbance characteristics of information technology equipment, Amendment 1 (1995) and

Amendment 2 (1996)

12/CIS22b

CNS 13438 (1997): Limits and Methods of Measurement of Radio Interference

Characteristics of Information Technology Equipment

12/FCC15b

ANSI C63.4 (2003) with FCC Method 47 CFR Part 15, Subpart B: Unintentional Radiators

12/T51

AS/NZS CISPR 22 (2002) and AS/NZS 3548 (1997): Electromagnetic Interference - Limits

and Methods of Measurement of Information Technology Equipment

Immunity Test Methods:

12/101

IEC 61000-4-2, Ed. 1.2 (2001) + A1, A2; EN 61000-4-2: Electrostatic Discharge Immunity

Test

12/102

IEC 61000-4-3, Ed. 2.0 (2002-03); EN 61000-4-3 (2002): Radiated Radio-Frequency

Electromagnetic Field Immunity Test

2005-07-01 through 2006-06-30

Effective dates

For the National Institute of Standards and Technology

Page 1 of 2

NVLAP-01S (REV. 2005-05-19)



National Voluntary Laboratory Accreditation Program



ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

NVLAP LAB CODE 200533-0

NVLAP Code	Designation / Description
12/I03	IEC 61000-4-4(1995), A1(2000), A2(2001); EN 61000-4-4: Electromagnetic compatibility (EMC) - Part 4-4: Testing and measurement techniques - Electrical Fast Transient/Burst Immunity Test
12/I04	IEC 61000-4-5, Ed. 1.1 (2001-04); EN 61000-4-5: Electromagnetic compatibility (EMC) - Part 4-5: Testing and measurement techniques - Surge immunity test
12/105	IEC 61000-4-6, Ed. 2.0 (2003-05); EN 61000-4-6: Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields
12/I06	IEC 61000-4-8, Ed. 1.1 (2001); EN 61000-4-8: Electromagnetic compatibility (EMC) - Part 4-8: Testing and measurement techniques - Power frequency magnetic field immunity test
12/I07	IEC 61000-4-11, Ed. 1.1 (2001-03); EN 61000-4-11: Voltage Dips, Short Interruptions and Voltage Variations Immunity Tests

2005-07-01 through 2006-06-30

Effective dates

For the National Institute of Standards and Technology